

<b>Notice of References Cited</b>	Application/Control No. 10/684,503	Applicant(s)/Patent Under Reexamination SAKAMOTO ET AL.	
	Examiner Richard Bueker	Art Unit 1763	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,796,562	01-1989	Brors et al.	118/725
*	B	US-5,273,588	12-1993	Foster et al.	118/723E
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Lee et al, Thin solid Films 262 (1995) 39-45.
	V	Keenan, General College Chemistry, Harper & Row, 1957, pages132-133.
	W	Powell et al., Vapor Deposition, John Wiley & Sons, 1967, pages 274-275 and 296-297.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.